

g

GE Energy

Functional Testing Specification*Parts & Repair Services
Louisville, KY***LOU-ATE1-DS200TCQC****Test procedure for a card tested on the ATE1 System****DOCUMENT REVISION STATUS:** Determined by the last entry in the "REV" and "DATE" column

REV.	DESCRIPTION	SIGNATURE	REV. DATE
A	Initial release	Eric Rouse	10/25/2001
B	Transferred procedure from a general group to a specific single document. Also added asset numbers to section 5.	Jeffrey Barton	8/16/2010
C	Added step 6.1 about replacing all relays and burn-in process on revitalization jobs and on Mark V operation	Jeffrey Barton	3/28/2014

© COPYRIGHT GENERAL ELECTRIC COMPANY

Hard copies are uncontrolled and are for reference only.

PROPRIETARY INFORMATION – THIS DOCUMENT CONTAINS PROPRIETARY INFORMATION OF GENERAL ELECTRIC COMPANY AND MAY NOT BE USED OR DISCLOSED TO OTHERS, EXCEPT WITH THE WRITTEN PERMISSION OF GENERAL ELECTRIC COMPANY.

PREPARED BY E. Rouse	REVIEWED BY J. Barton	REVIEWED BY	QUALITY APPROVAL <i>Charlie Wade</i>
DATE 10/25/2001	DATE 8/16/2010	DATE	DATE 8/16/2010

Functional test procedure for an ATE tested item.

1. SCOPE

1.1 This is a functional test procedure for cards that are developed to be tested on ATE1.

2. STANDARDS OF QUALITY

2.1 Refer to the current revision of the IPC-A-610 standard for workmanship standards.

3. APPLICABLE DOCUMENTS

3.1 The following document(s) shall form part of this specification to the extent specified herein. Unless otherwise indicated, the latest issue shall apply.

3.1.1 Check board's electronic folder for more information

4. ENGINEERING REQUIREMENTS

4.1 Equipment Cleaning

4.1.1 Equipment should be clean and free of debris prior to applying power unless performing an initial check. Refer to site specific SRA's for cleaning guidelines.

4.2 Equipment Inspection

4.2.1 Equipment should be visually inspected for any defects prior to applying power. This inspection should include the following as a minimum:

4.2.1.1 Wires broken or cracked

4.2.1.2 Terminal strips / connectors broken or cracked

4.2.1.3 Loose wires

4.2.1.4 Components visually damaged

4.2.1.5 Capacitors leaking

4.2.1.6 Solder joints damaged or cold

4.2.1.7 Circuit board burned or de-laminated

4.2.1.8 Printed wire runs burned or damaged

5. EQUIPMENT REQUIRED

5.1 The following equipment is required to perform the process requirements. Equipment may be substituted provided that all accuracy's and test ratios are equivalent or better.

Qty	Reference #	Description
1	H033779	ATE1
1	H033891	Fixture Box
1	#48	Personality Module

<p>LOU-ATE1-DS200TCQC REV. C</p>	<p>g</p> <p>GE Energy Parts & Repair Services Louisville, KY</p>	<p>Page 3 of 3</p>
---	--	---------------------------

6. TESTING PROCESS

6.1 Setup

6.1.1 For all revitalization jobs please replace all relays. May need to use Chipquik.

Relay 218A4625P1+SP 2 pieces

Relay 104X166AA082 6 pieces

6.2 Testing Procedure

6.2.1 As required by ATE instructions

6.2.2 Identify the test to be used on the ATE by matching the model number with the ones on the system and follow the instructions given after execution.

6.3 Mark V operation

6.3.1 Verify that the core boots and condition is A7 via the SLCC display



6.3.2

6.4 Burn-in Time.

6.4.1 Burn-in time for Mark V cards normal repair

6.4.2 DS200TCQC 1 hour minimum in Mark V rack

6.4.3 Burn-in time for Mark V cards Revitalization Program

6.4.4 DS200TCQC 3 hours minimum in Mark V rack

6.5 *****TEST COMPLETE*****

7. NOTES

7.1 Changes to the electronic ATE test are recorded in the [Software Control Database](#)

8. Attachments

8.1 None at this time.